

N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS}	40	V		
$R_{DS(on)} V_{GS} = 10 V$	6	mΩ		
I _D	110	Α		
Configuration	Single			

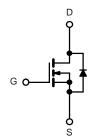
FEATURES

- TrenchFET® Power MOSFET
- 100 % R_g and UIS Tested

RoHS

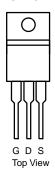
APPLICATIONS

- Synchronous Rectification
- Power Supplies



N-Channel MOSFET

$T \sim$	-220	



ABSOLUTE MAXIMUM RATINGS	T _A = 25 °C, unle	ss otherwise no	ted	
Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	40	V
Gate-Source Voltage		V _{GS}	± 20	7 v
	T _C = 25 °C		110 ^{a, c}	
Continuous Proin Current (T = 175 °C)	T _C = 70 °C	, F	90°	
Continuous Drain Current (T _J = 175 °C)	T _A = 25 °C	I _D	31 ^b	A
	T _A = 70 °C		25 ^b	
Pulsed Drain Current	I _{DM}	270		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	85	
Single Pulse Avalanche Energy	L = 0.1 IIII	E _{AS}	320	V
Continuous Source-Drain Diode Current	T _C = 25 °C	L	110 ^{a, c}	A
	T _A = 25 °C	I _S	2.6 ^b	
Maximum Power Dissipation	T _C = 25 °C		312 ^a	
	T _C = 70 °C	ь Г	200	
	T _A = 25 °C	P _D	3.13 ^b	W
	T _A = 70 °C		2.0 ^b	1
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^b	Steady State	R _{thJA}	32	40	°C/W
Maximum Junction-to-Case	Steady State	R_{thJC}	0.33	0.4]

Notes:

- a. Based on $T_C = 25$ °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. Calculated based on maximum junction temperature. Package limitation current is 110 \mbox{A} .



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static					I	1
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	40			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 250 A		41		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 8		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.2		2.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zana Cata Maltana Busin Comment		$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$	GS = 0 V		1	μA
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α
D : 0	В	$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$		6		
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 20 \text{ A}$		7		mΩ
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 15 \text{ V}, I_{D} = 30 \text{ A}$		180		S
Dynamic ^b						
Input Capacitance	C _{iss}			2900		
Output Capacitance	C _{oss}	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		750		pF
Reverse Transfer Capacitance	C _{rss}			310		
Total Gate Charge	Qg			130		
Gate-Source Charge	Q_{gs}	$V_{DS} = 20 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 20 \text{ A}$		20		nC
Gate-Drain Charge	Q_{gd}			32		1
Gate Resistance	R _g	f = 1 MHz		0.85	1.3	Ω
Turn-On Delay Time	t _{d(on)}			20	30	
Rise Time	t _r	V_{DD} = 20 V, R_L = 1.0 Ω		11	17	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 20$ A, V_{GEN} = 10 V, R_g = 1 Ω		77	115	
Fall Time	t _f			10	15	1
Turn-On Delay Time	t _{d(on)}			102	155	ns
Rise Time	t _r	V_{DD} = 20 V, R_L = 1.0 Ω		62	95	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 20$ A, V_{GEN} = 4.5 V, R_g = 1 Ω		180	270	
Fall Time	t _f			60	90	1
Drain-Source Body Diode Characteristic	cs				L	
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			110	^
Pulse Diode Forward Current ^a	I _{SM}				200	A
Body Diode Voltage	V_{SD}	I _S = 20 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			50	75	ns
Body Diode Reverse Recovery Charge	Q _{rr}	L = 20 A di/dt = 100 A/vo T = 25 °C		70	105	nC
Reverse Recovery Fall Time	ta	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		30		ns
Reverse Recovery Rise Time	t _b			20		

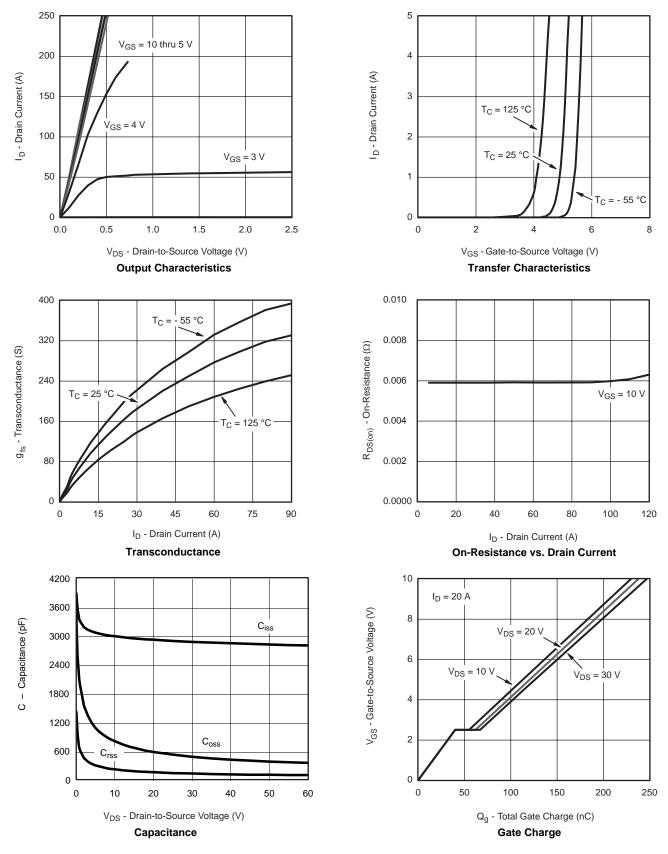
Notes:

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

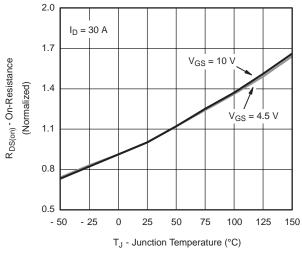


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

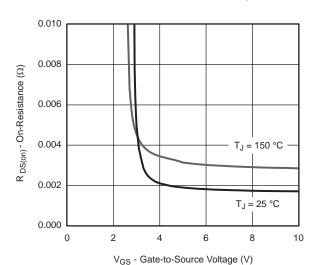




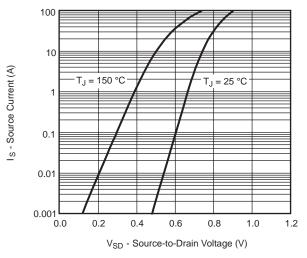
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On-Resistance vs. Junction Temperature



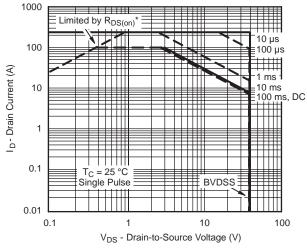
On-Resistance vs. Gate-to-Source Voltage



Forward Diode Voltage vs. Temperature



Threshold Voltage

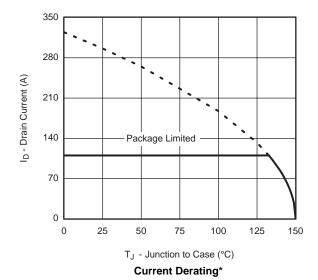


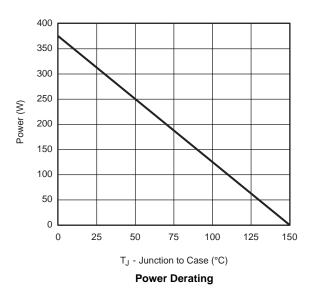
 * V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient

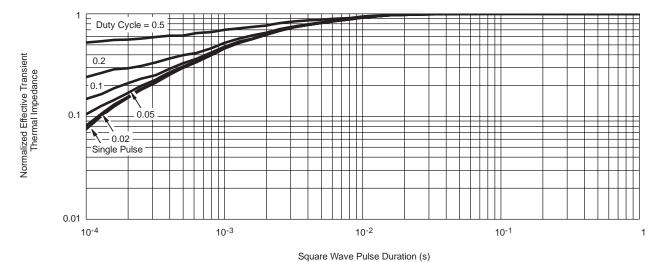


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





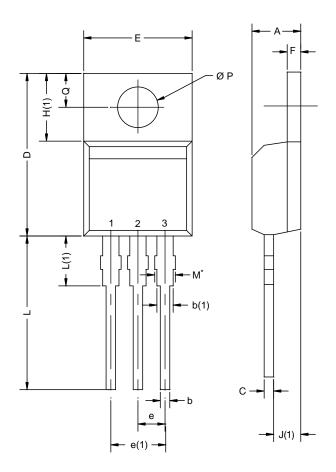
* The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case



TO-220AB



	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
С	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
Е	10.04	10.51	0.395	0.414
е	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
ØР	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471				

Notes

 $^{^{\}star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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